

Class  
Subclass  
Issue Classification

5962369

UTILITY SERIAL NUMBER 00/183800 PATENT OCT 05 1999 PATENT NUMBER

01 800 1/94 25 SUBCLASS 49 GROUP ART UNIT 2508 2800 EXAMINER CRANE

SHUNPEI YAMAZAKI, TOKYO, JAPAN; HONGYONG ZHANG, KANAGAWA, JAPAN; NAOTO KUSUMOTO, KANAGAWA, JAPAN; YASUHIKO TAKEMURA, KANAGAWA, JAPAN.

\*\*CONTINUING DATA\*\*\*\*\*  
VERIFIED THIS APPLN IS A CON OF 07/852,517 03/17/92 ABN  
AND A CIP OF 07/933,718 8/24/92 U.S. Patent No. 5,296,405  
WHICH IS A CON OF 07/520,998 5/9/90 U.S. Patent No. 5,171,710  
WHICH IS A CIP OF 07/251,940 9/28/88 U.S. Patent No. 4,986,213  
WHICH IS A CON OF 06/891,791 8/1/96 ABN

\*\*FOREIGN/PCT APPLICATIONS\*\*\*\*\*  
VERIFIED FED REP GERMANY 3-80799 03/18/91  
JAPAN

NOTE/DISCLAIMER  
The term of this patent shall not extend beyond the expiration date of Pat. No. 5,262,654.

Foreign priority claimed: ☒ yes ☐ no  
35 USC 119 conditions met: ☒ yes ☐ no  
AS FILED STATE OR COUNTRY JPX SHEETS DRWGS. 6 TOTAL CLAIMS 15 INDEP. CLAIMS 4 FILING FEE RECEIVED \$784.00 ATTORNEY'S DOCKET NO. 0756958

STIXBEY, FRIEDMAN, LEEDOM & FERGUSON  
2010 CORPORATE RIDGE  
SUITE 600  
MCLEAN, VA 22102

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SEMICONDUCTOR MATERIAL AND METHOD FOR FORMING THE SAME AND THIN FILM TRANSISTOR

U.S. DEPT. of COMM. Pat. & TM. Office PTO-436L (rev. 10-78)

PARTS OF APPLICATION FILED SEPARATELY  
Applications Examiner

NOTICE OF ALLOWANCE MAILED  
4-13-99  
Assistant Examiner

ISSUE FEE  
Amount Due 1200 Date Paid 12-15-99  
Primary Examiner Sara Crane

CLAIMS ALLOWED  
Total Claims 34  
Print Claim  
DRAWING  
Sheets Drawn 6 Figs. Drawn 8 Printed

ISSUE BATCH NUMBER R-78

PREPARED FOR ISSUE

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Form PTO-436A  
(Rev. 8/92)

FORMAL FEE IN FILE

Formal Drawings ( sheets) set

(FACE)

PATENT NUMBER

## ORIGINAL CLASSIFICATION

CLASS

SUBCLASS

APPLICATION SERIAL NUMBER

08/183,800

## CROSS REFERENCE(S)

CLASS

SUBCLASS

(ONE SUBCLASS PER BLOCK)

APPLICANT'S NAME (PLEASE PRINT)

YAMAZAKI ET AL.

IF REISSUE, ORIGINAL PATENT NUMBER

## INTERNATIONAL CLASSIFICATION

H01L 29/04

GROUP  
ART UNIT

2811

ASSISTANT EXAMINER (PLEASE STAMP OR PRINT FULL NAME)

PRIMARY EXAMINER (PLEASE STAMP OR PRINT FULL NAME)

SARA W. CRANE

TO 270  
(REV. 5-91)

ISSUE CLASSIFICATION SLIP

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